



Faculty of Engineering
Cairo University



Electronics project

Submitted to

DR: Mohamed Abdullah yousef

ENG:Hesham Amin

<u>Name</u>	<u>SEC</u>	<u>B.N</u>
بلال محمد ابراهيم فوزي	<u>2</u>	<u>2</u>
صالح رمضان صالح عثمان	<u>2</u>	<u>49</u>
عبدالرحمن احمد سعد حسن	<u>2</u>	<u>54</u>

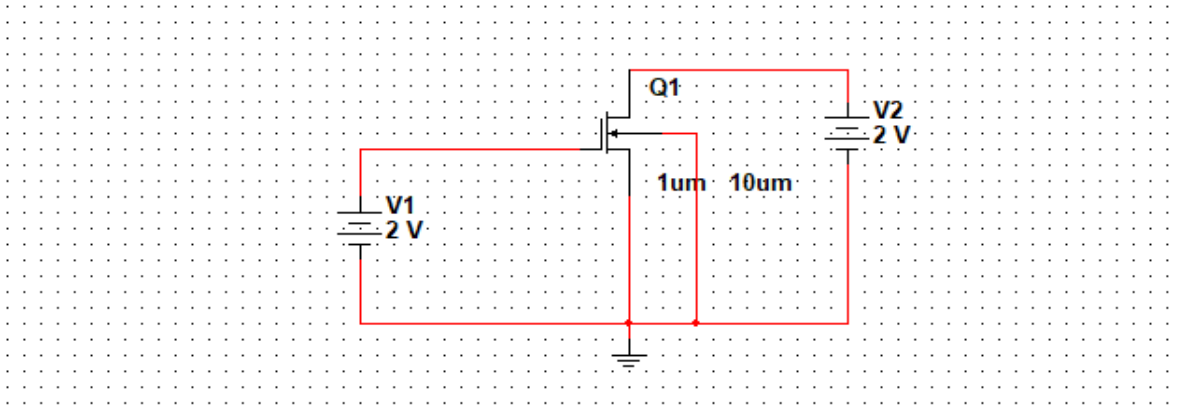
يوجد جداول ملخص نتائج في نهاية كل مسألة للتسهيل

Q1.Transistor Characterization:

In this problem we need to determine the parameters for Mos like μ_{cox} & λ & V_{TH} for both NMOS & PMOS and compare between results:

NMOS:

a) $W=10\mu\text{m}$ & $L=1\mu\text{m}$



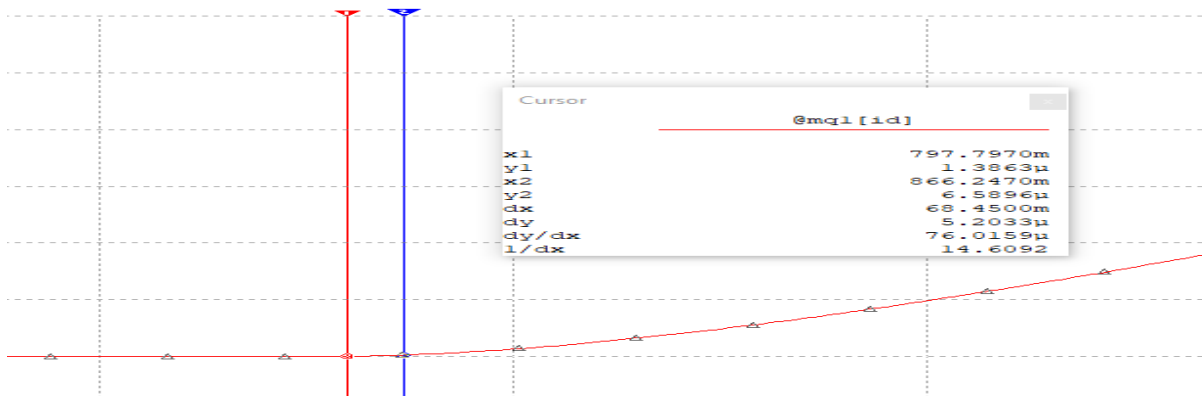
(1) Schematic diagram

Design Procedure & Simulation results:

$V_{\text{in}}=V_{\text{GS}}$, $V_{\text{out}}=V_{\text{DS}}$ (as V_{S} is grounded) we also connect the substrate to the least voltage in circuit so we connect it to ground.

1.First case:

we will sweep V_{in} from (0 to 3V) while $V_{\text{out}}=2\text{V}$, in this case we will study the variations of I_{DS} with V_{GS} so we can determine V_{TH} , and this is the result of simulation:

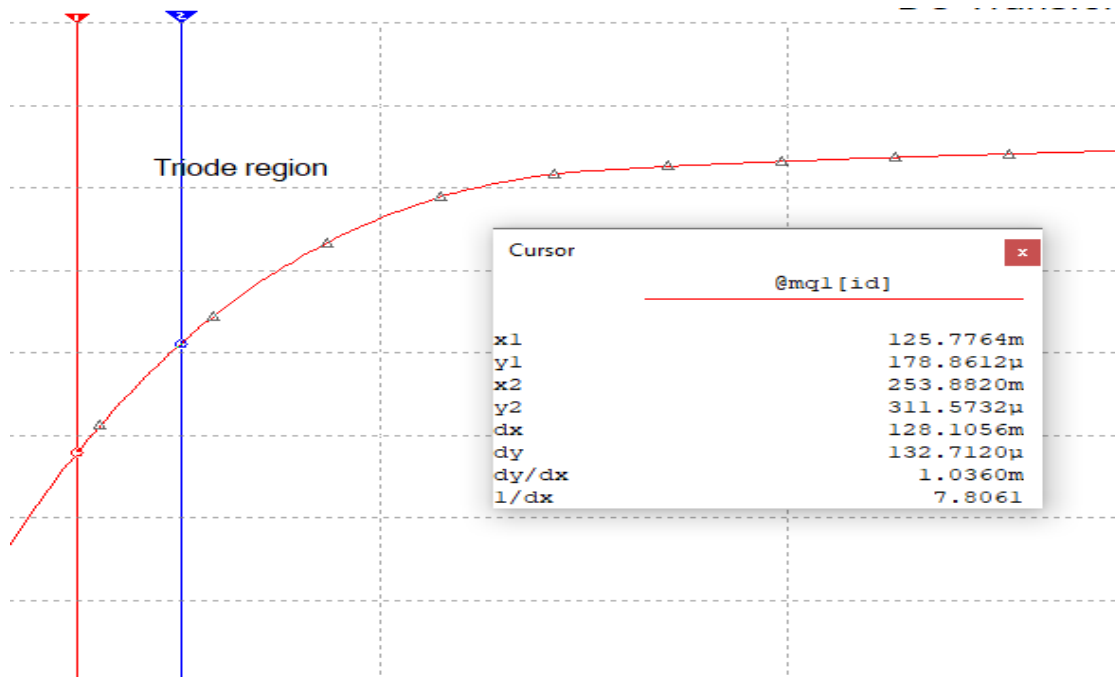


(2) "The relation between I_{DS} & V_{GS} "

From this curve we can determine V_{TH} as it is the value for V_{GS} to be a significant value for I_{DS} , from figure (2) we found that: $V_{TH}=0.798V$

2.Second case:

we will sweep V_{out} from (0 to 3V) while $V_{in}=2V$, in this case we will study the variations of I_{DS} with V_{DS} so we can determine μnC_{ox} from the triode region and λ from the saturation region, and this is the result of simulation:



(3)“The relation between I_{DS} & V_{DS} in triode region”

From the equation of the current in Triode region:

$$I_{DS} = \mu n C_{ox} (W/L) (V_{GS} - V_{TH}) V_{DS} - V_{DS}^2 / 2$$

We can neglect the squaring term of V_{DS} and then we can from this equation determine $\mu n C_{ox}$ as the slope of figure(3) equals

$$\mu n c_{ox}(W/L)(V_{GS}-V_{TH})$$

We can obtain $\mu n c_{ox}$:

$$\mu n C_{ox} = \text{slope} / ((W/L) (V_{GS} - V_{TH}))$$

$$(W/L)=10, V_{GS}-V_{TH}=2-0.798=1.202 V, \text{slope}=1.0360 \text{ mm}$$

$$\mu n C_{ox} = 8.62 \times 10^{-5}$$

And we will calculate λ from the equation of current in saturation region:

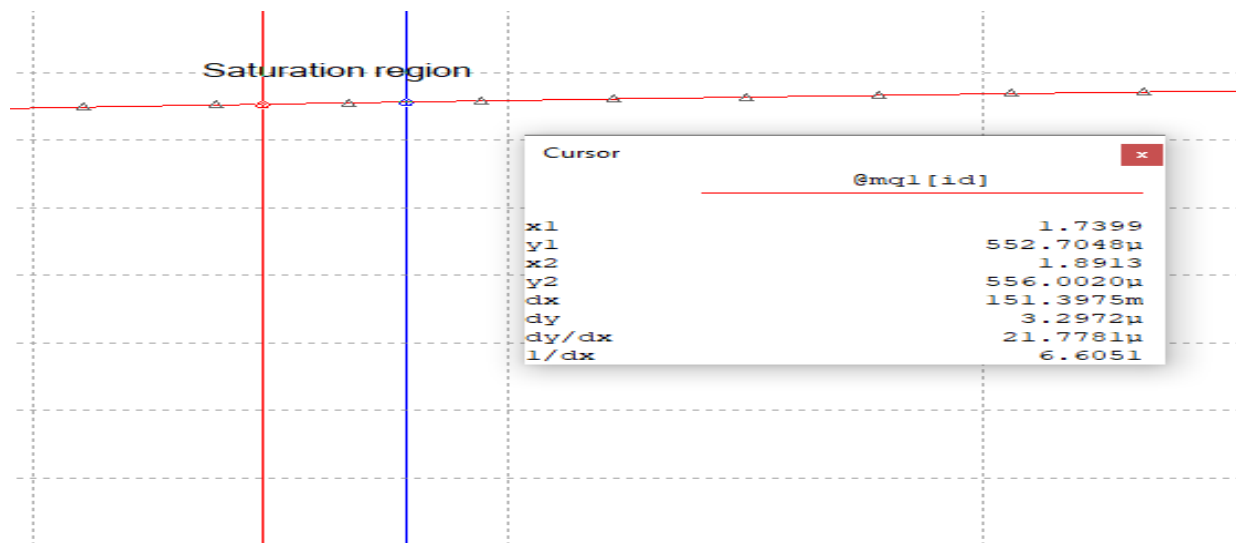
$$I_{DS} = 0.5 \mu_n C_{ox} (W/L) ((V_{GS} - V_{TH})^2 (1 + \lambda V_{DS}))$$

So we can get the slope of the curve in sat region then

$$\lambda = \text{slope} / R_S$$

$$\text{Where } R_S = 0.5 \mu_n C_{ox} (W/L) ((V_{GS} - V_{TH})^2)$$

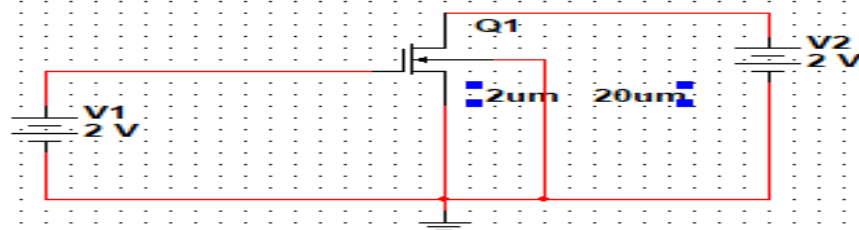
The slope from simulation results:



(4) "The relation between I_{DS} & V_{DS} in Sat region"

Slope=21.7781μ then: $\lambda = 0.035$

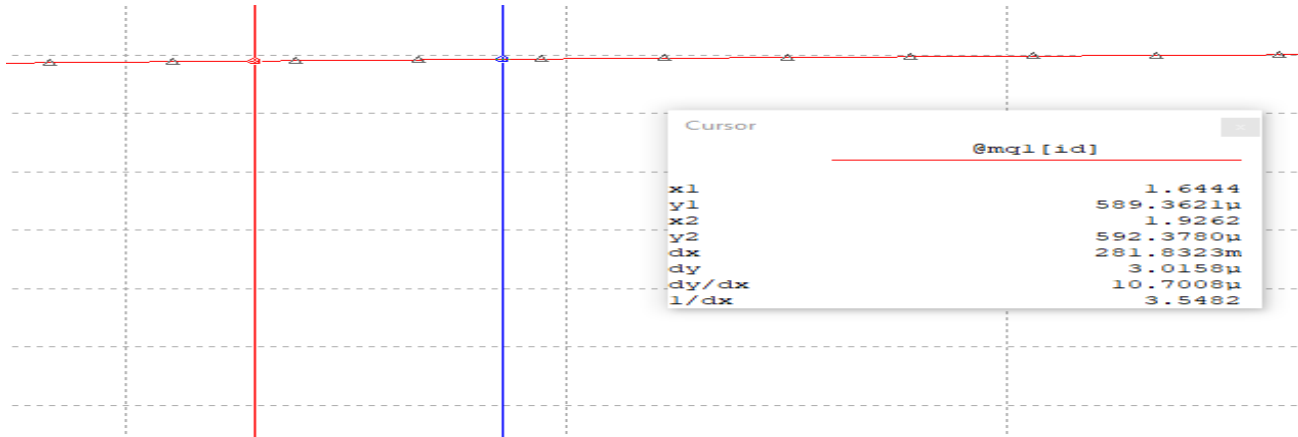
b) $W=20\mu\text{m}$ & $L=2\mu\text{m}$



(5) schematic

DISSCUTION:

For the value of V_{TH} it doesn't change as this value depends on the the temperature and the fabrication of the MOSEFT ,for μ_{ncox} it also doesn't change as it depends also on another parameters not related to length and width of the MOSEFT and if, it depends on the ratio between them and in our case it is still the same the ratio between length and width, for λ it will change as λ depends on the length of the MOS ($\lambda \propto (1/L)$) so when L increase the λ will decrease and the curve in sat region will be more flatter as shown:



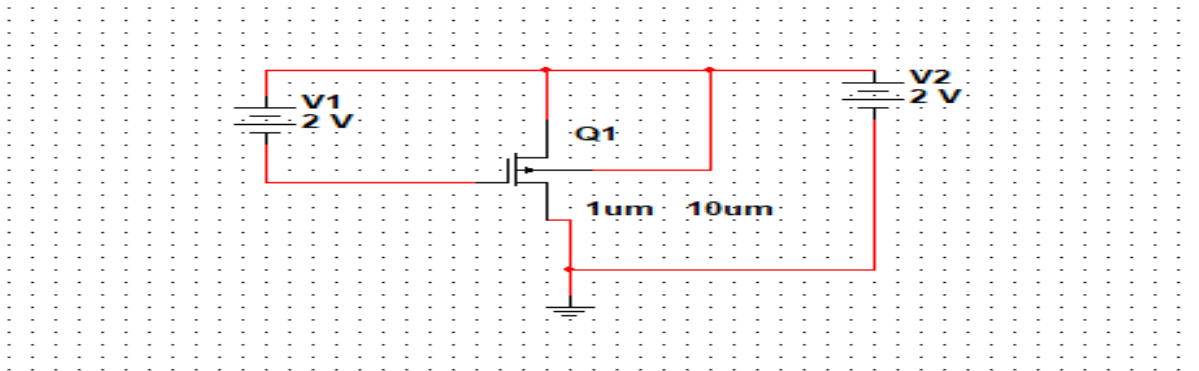
(6) "The relation between IDS &VDS in Sat region"

Slope=10.7u

So $\lambda=0.017$

PMOS:

a) $W=10\mu\text{m}$ & $L=1\mu\text{m}$



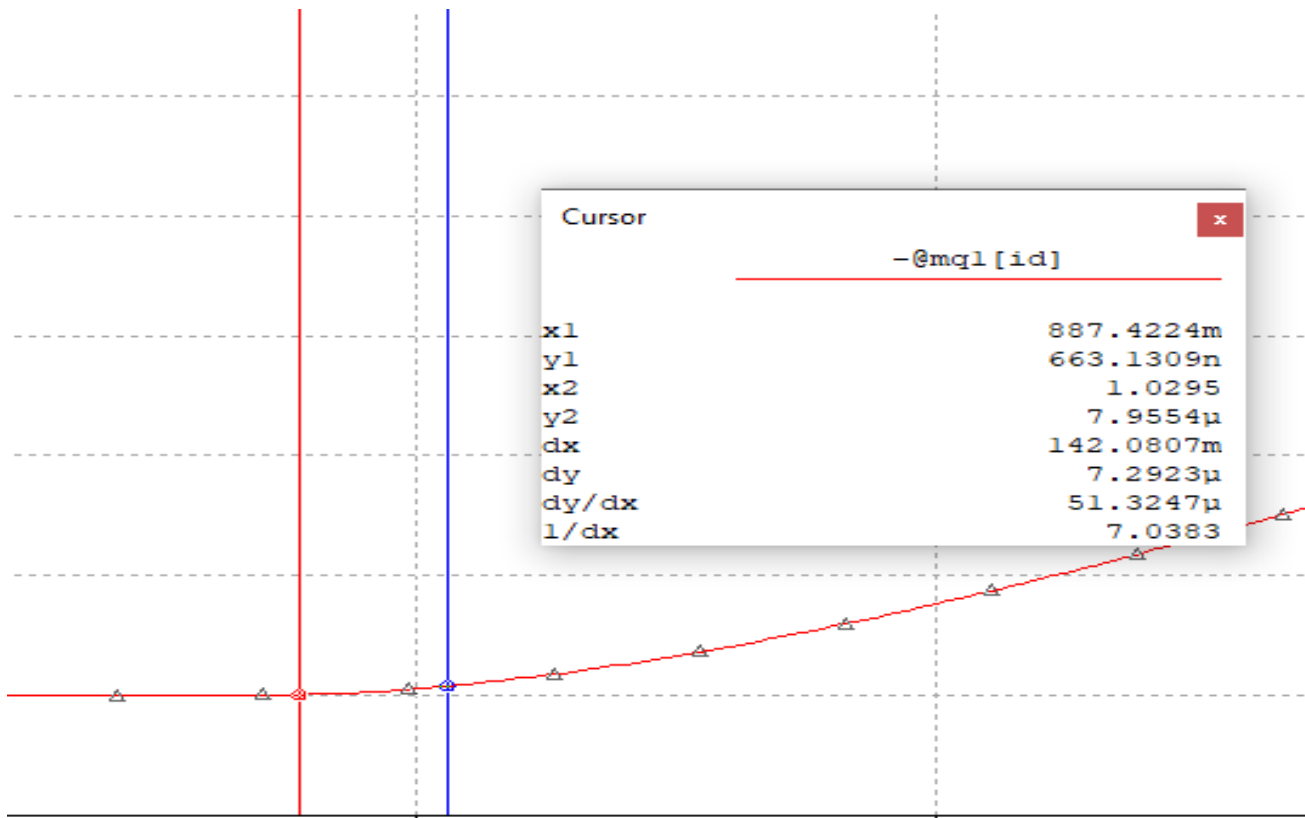
(7)pmos schematic

Design Procedure & Simulation results:

$V_{in}=V_{SG}$, $V_{out}=V_{SD}$ (as V_D is grounded) we also connect the substrate to the most voltage in circuit.

1.First case:

We will do as we did in NMOS :

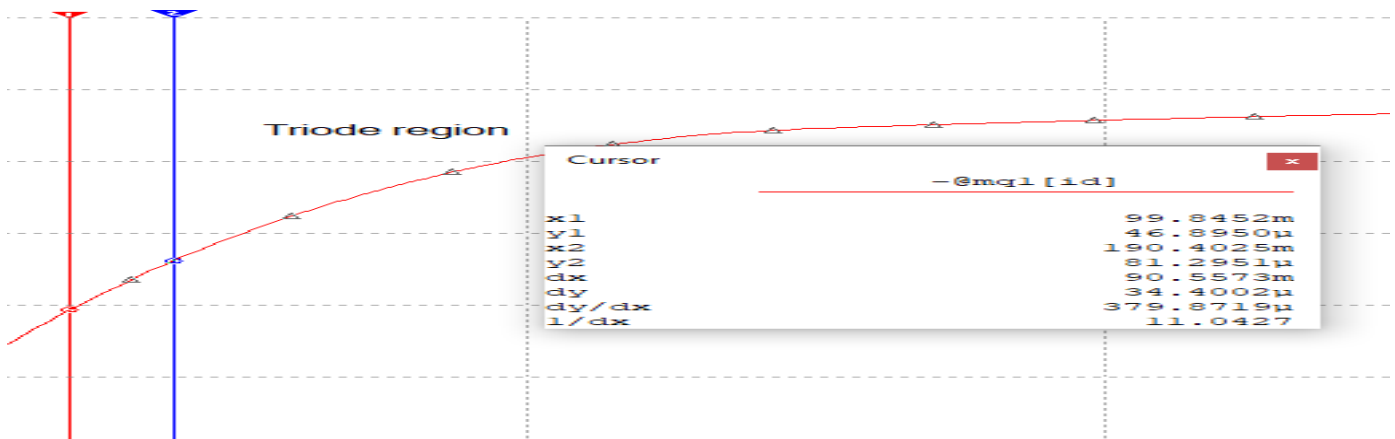


(8)“The relation between VSG&ISD”

From this curve we can determine V_{THp} as it is the value for VSG to be a significant value for ISD, from figure (8) we found that: $|V_{THp}|=0.887V$

2.Second case:

We will do as we did in NMOS:



Figure(9) “The relation between ISD &VSD in triode region”

From the equation of the current in Triode region:

$$I_{SD} = \mu_{pcox}(W/L)((V_{SG} - |V_{THp}|)V_{SD} - V_{SD}^2/2)$$

We can neglect the squaring term of VSD and then we can from this equation determine μ_{pcox} as the slope of figure(9) equals

$$\mu_{pcox}(W/L)(V_{SG} - |V_{THp}|)$$

We can obtain μ_{pcox} :

$$\mu_{pcox} = \frac{\text{slope}}{(W/L)(V_{SG} - |V_{THp}|)}$$

$$(W/L)=10, \quad v_{sg}-|v_{thp}|=2-0.887=1.113 \text{ V}, \quad \text{slope}=379.87 \text{ um}$$

$$\mu_{pcox} = 3.4 \times 10^{-5}$$

And we will calculate λ from the equation of current in saturation region:

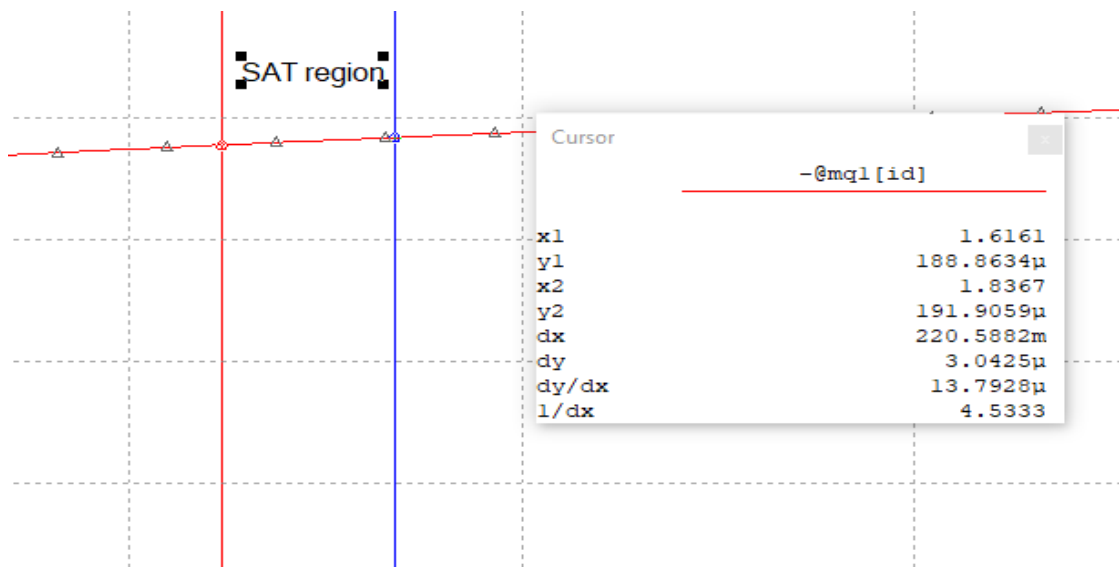
$$I_{SD} = 0.5 \mu_{pcox}(W/L)((V_{SG} - |V_{THp}|)^2(1 + \lambda V_{SD}))$$

So we can get the slope of the curve in sat region then

$$\lambda = \text{slope}/RS$$

$$\text{Where } RS = 0.5 \mu_{pcox}(W/L)((V_{SG} - |V_{THp}|)^2)$$

The slope from simulation results:



Figure(10) "The relation between I_{SD} & V_{SD} in SAT region"

$$\text{Slope}=13.7938 \text{ um then: } \lambda = 0.066$$

b) $W=20\mu\text{m}$ & $L=2\mu\text{m}$

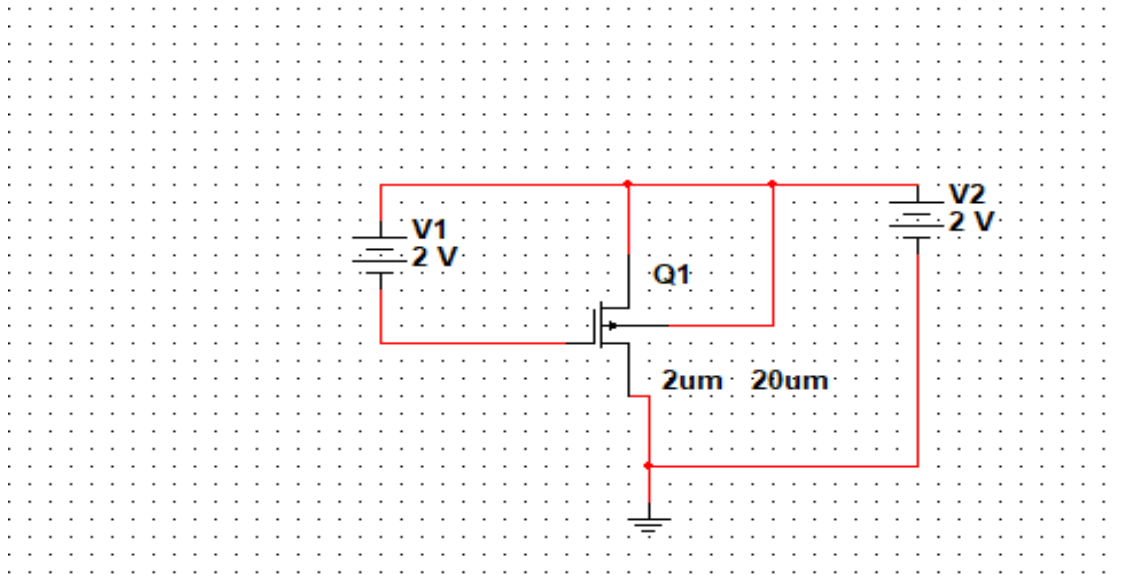
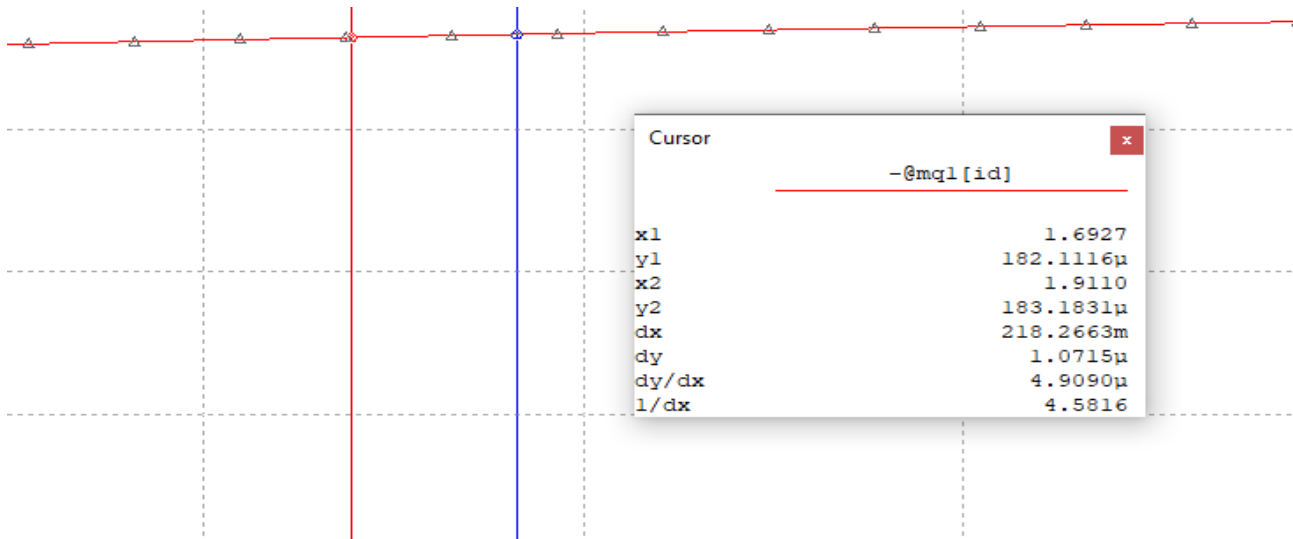


Figure (11)

DISSCUSSION:

For the value of $|V_{THp}|$ it doesn't change as this value depends on the the temperature and the fabrication of the MOSEFT ,for μ_{pcox} it also doesn't change as it depends also another parameters not related to length and width of the MOSEFT and if, it depends on the ratio between them and in our case it is still the same the ratio between length and width, for λ it will change as λ depends on the length of the MOS ($\lambda \propto (1/L)$) so when L increase the λ will decrease and the curve in sat region will be more flatter as shown:



Figure(12)

Slope=4.909um

So $\lambda=0.023$

SUMMARY&CONCLUSTIONS:

NMOS	VTH	μ_{cox}	λ
W=10um L=1um	0.798	8.62×10^{-5}	0.035
W=20um L=2um	0.798	8.62×10^{-5}	0.017
PMOS			
W=10um L=1um	0.887	3.4×10^{-5}	0.066
W=20um L=2um	0.887	3.4×10^{-5}	0.023

THE comparison between PMOS &NMOS:

1-VTH of PMOS is a little bit more than NMOS

2- μ_{cox} of NMOS is more than PMOS as the mobility of electrons is more than the mobility of holes

3-the channel length modulation of PMOS is more than NMOS and this cause in NMOS the curve of current in sat region is more flatter as it has a small λ

And this decrease the percentage error for example in current mirror

4-for both NMOS& PMOS when the length of MOS increase

Channel length modulation decrease and the error decrease but as we knew in current mirrors when we increase L that will effect on compliance voltage and these are the trades off design.

Q2.Current Mirrors:

a) Simple Current Mirror

1.First Case

we are given that:

$I_{in}=100\mu A$, $I_{out}=200\mu A$, $V_{eff}=0.25$, $L=1\mu m$ for both

We need to determine the width of each transistor:

To operate these transistors as current mirrors they should be in sat

So by using the equation of current in saturation we can obtain W

For M1 : $I_{DS}|_{in} = 0.5 \mu n C_{ox} (W/L) ((V_{GS}-V_{TH})^2$

We have $\mu n C_{ox}=8.62 \times 10^{-5}$

Then $W_1=37\mu m$ then from mirroring $W_2=74\mu m$

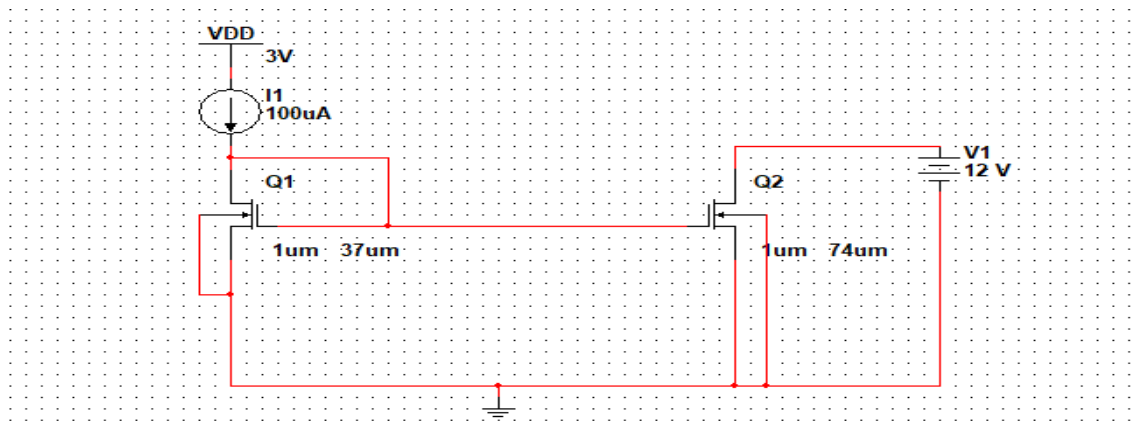
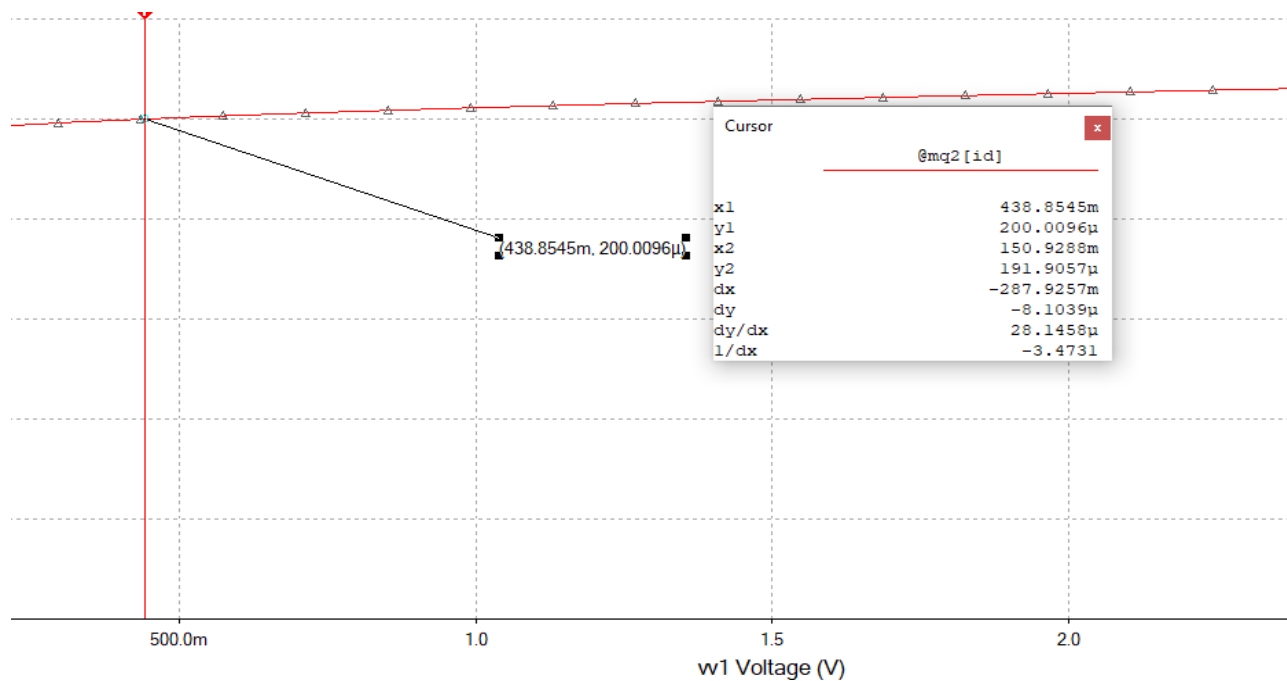


Figure (13)

Compliance voltage is the min value for V_{out} for the circuit to operate as a current mirror. In our case to operate M2 in SAT it needs as a min value $V_{DS sat}$ that equals V_{eff} , and in this problem $V_{out}=V_{DS}$ then $V_{out min}=V_{DS sat}=V_{eff}$.

Then $V_{comp.}=0.25 V$ this value we get it through hand calculations let us get by plotting

I_{out} and V_{out} and the value of v_{out} that we get the output current $200\mu m$ it will be the compliance voltage and this is the simulation results:



Figure(14)

From the simulation result we can find that: $V_{comp}=0.44V$ this is the exact min value of v_{out} to be a $200\mu A$ in M2, the compliance voltage that we get from hand calculations will allow to be $197.38671\mu A$ only in M2 and this is the simulation result of DC operating point when we put the $v_{out}=0.25V$ that means M2 enters the SAT region.

DC Operating Point		
1	@mq2[id]	197.38671 u

Figure(15)

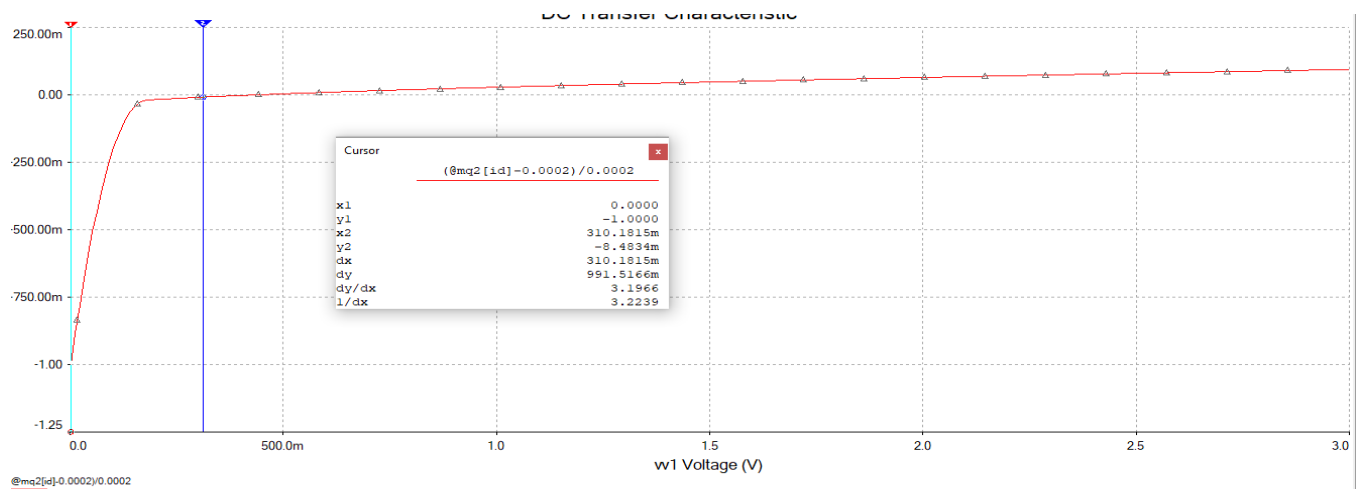
Then we can obtain the percentage error of the current relative to ideal current:

$$\text{Error} = \left(\frac{|I_{\text{actual}} - I_{\text{ideal}}|}{I_{\text{ideal}}} \right) \times 100$$

$$\text{Error} = \left(\frac{|197.38671 - 200|}{200} \right) \times 100$$

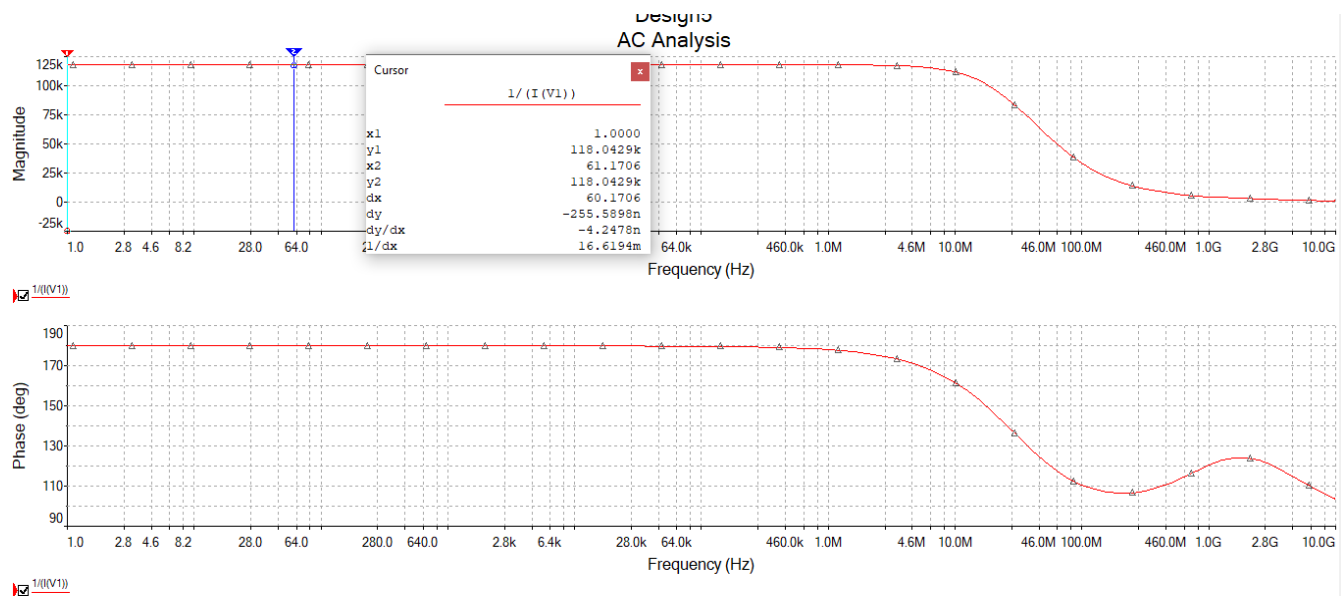
$$\text{Error} = 1.3\%$$

If we need to plot the percentage error with V_{out} , this is the simulation result:



Figure(16)

We need to determine R_{out} then we will do AC analysis with AC voltage source that the voltage offset of it is more compliance voltage for example (1 V) and this the result simulation:



Figure(17)

From simulation result $R_{out}=118K\Omega$

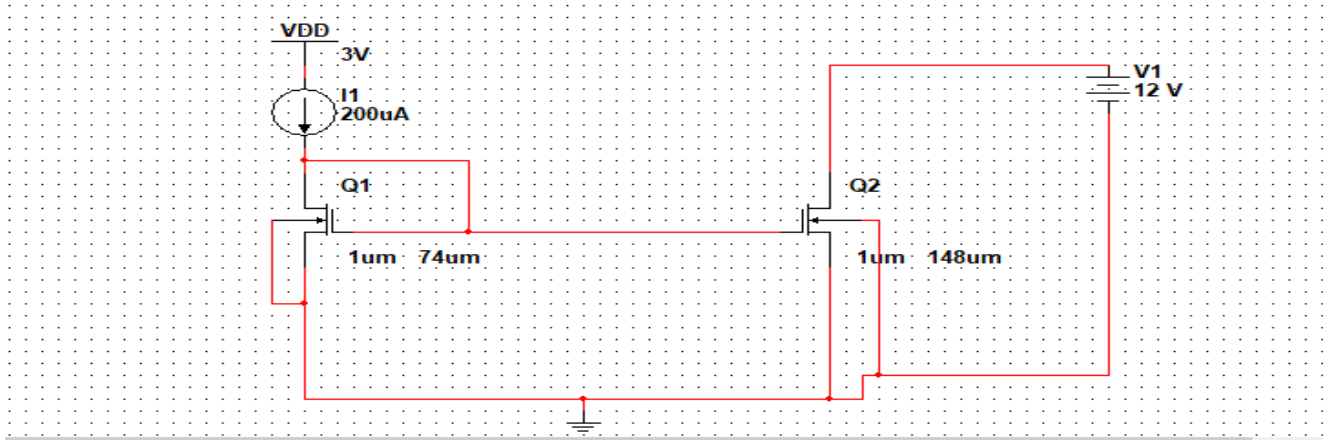
2.Second Case: $I_{in}=200\mu A$ & $I_{out}=400\mu A$ & $v_{eff}=0.25 V$ & $l=1\mu m$

We need also to determine W by using the equation of current in saturation we can obtain W

For M1 : $I_{DS}|_{in} = 0.5 \mu n C_{ox} (W/L) ((V_{GS}-V_{TH})^2$

We have $\mu n C_{ox}=8.62 \times 10^{-5}$

Then $W_1=74\mu m$ then from mirroring $W_2=148\mu m$



Figure(18)

We will repeat what we did in first case:

For compliance voltage by hand caluclations remains the same $V_{comp}=0.25V$

Let plot the relation between I_{out} & V_{out} to obtain the exact value for compliance voltage tha will be the value for v_{out} at $I_{out}=400uA$ and this the simulation result:

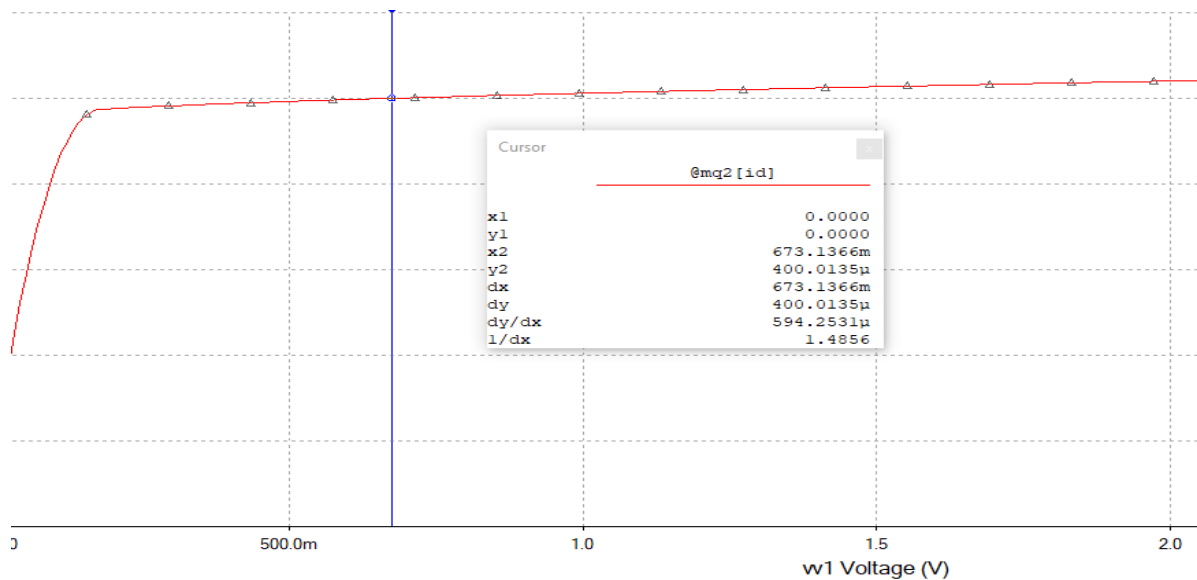


Figure (19)

We found that $V_{comp}=0.67V$

If we need to know the actual current that I_{out} will be when M2 enters the sat we put the v_{out} with 0.25 V and check DC operating point we found that:

DC Operating Point		
1	@mq2[id]	389.75649 u

Figure(20)

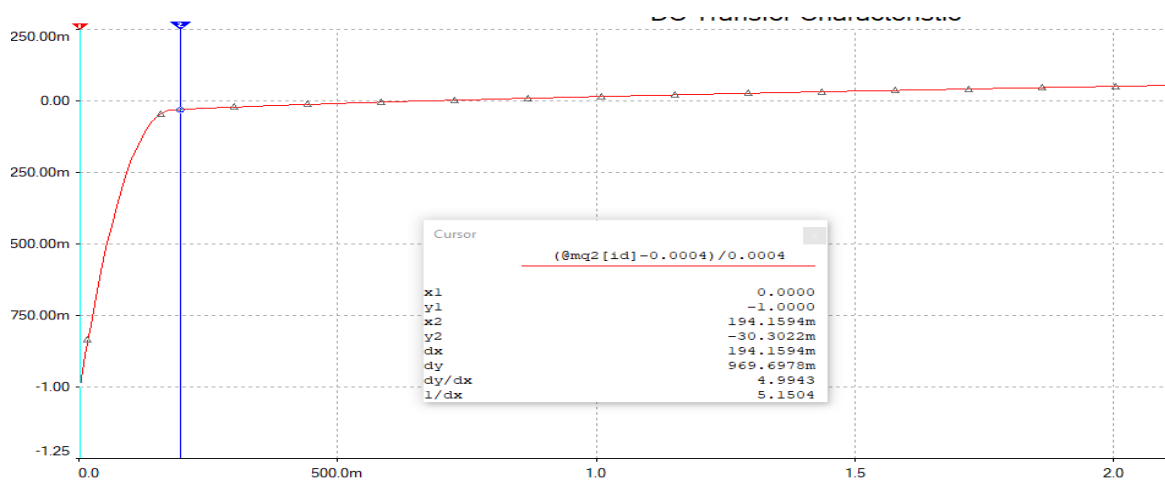
So we found that actual current will be $I_{actual}=389.75649\mu A$

$$\text{Error} = ((|I_{actual} - I_{ideal}|) / I_{ideal}) \times 100$$

$$\text{Error} = ((|389.75649 - 400|) / 400) \times 100$$

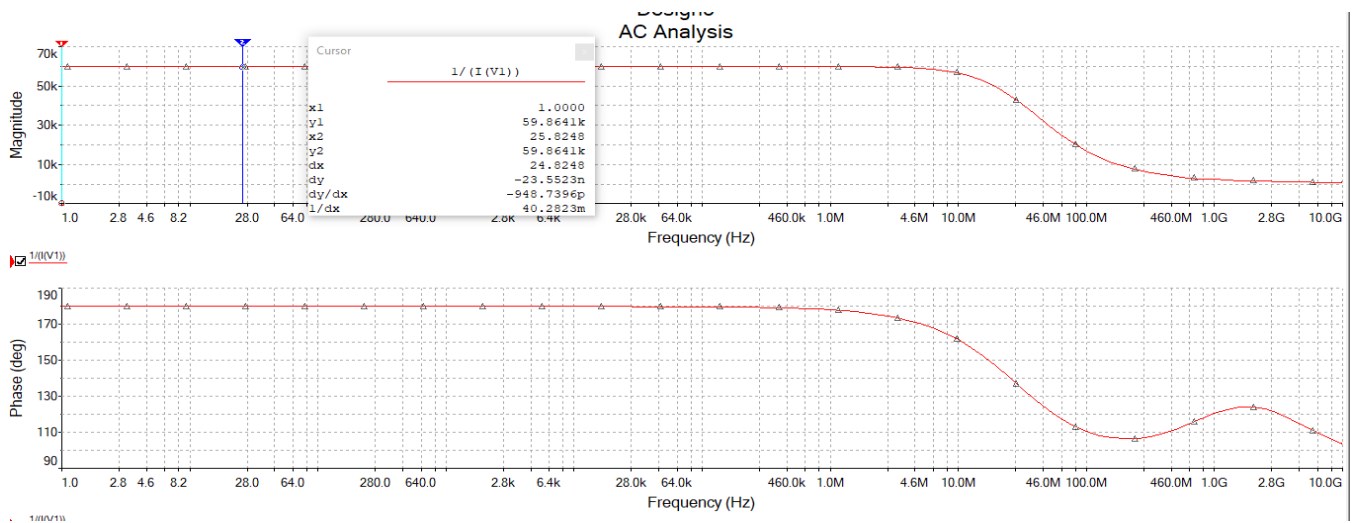
$$\text{Error} = 2.56\%$$

If we need to plot the percentage error with V_{out} , this is the simulation result:



Figure(21)

We need to determine R_{out} then we will do AC analysis with AC voltage source that the voltage offset of it is more compliance voltage for example (1 V) and this the result simulation:



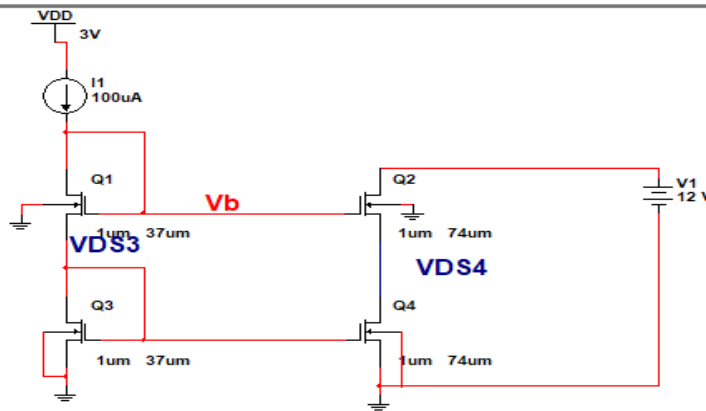
Figure(22)

From simulation result $R_{out}=60K\Omega$

b) Cascode Current Mirror:

1.First Case:

$I_{in}=100\mu A$, $I_{out}=200\mu A$



Figure(23)

In simple current mirror we neglected the term of λV_{DS} and this cause error in mirroring we need to increase the accuracy of mirroring so we made a cascode current mirror to increase accuracy of mirroring but this how happens:

In simple current mirror we made V_{GS} of two transistors are equal to take the term of λV_{DS} in consideration to increase accuracy of mirroring so we need that $V_{DS3}=V_{DS4}$ to reach high accuracy let's see that condition is satisfied or not:

All transistors have the same V_{GS} :

$V_b = 2V_{GS}$

$V_{DS3} = V_{GS}$

$V_{DS4} = V_b - V_{GS} = V_{GS}$ then $V_{DS3} = V_{DS4}$

Then we get high accuracy but we lose in compliance voltage

Let us obtain V_{comp} :

We need M2 to be in sat then: $V_{D4min} = V_{out\ min} = V_G - V_{TH}$

$V_G = V_b = 2V_{GS}$

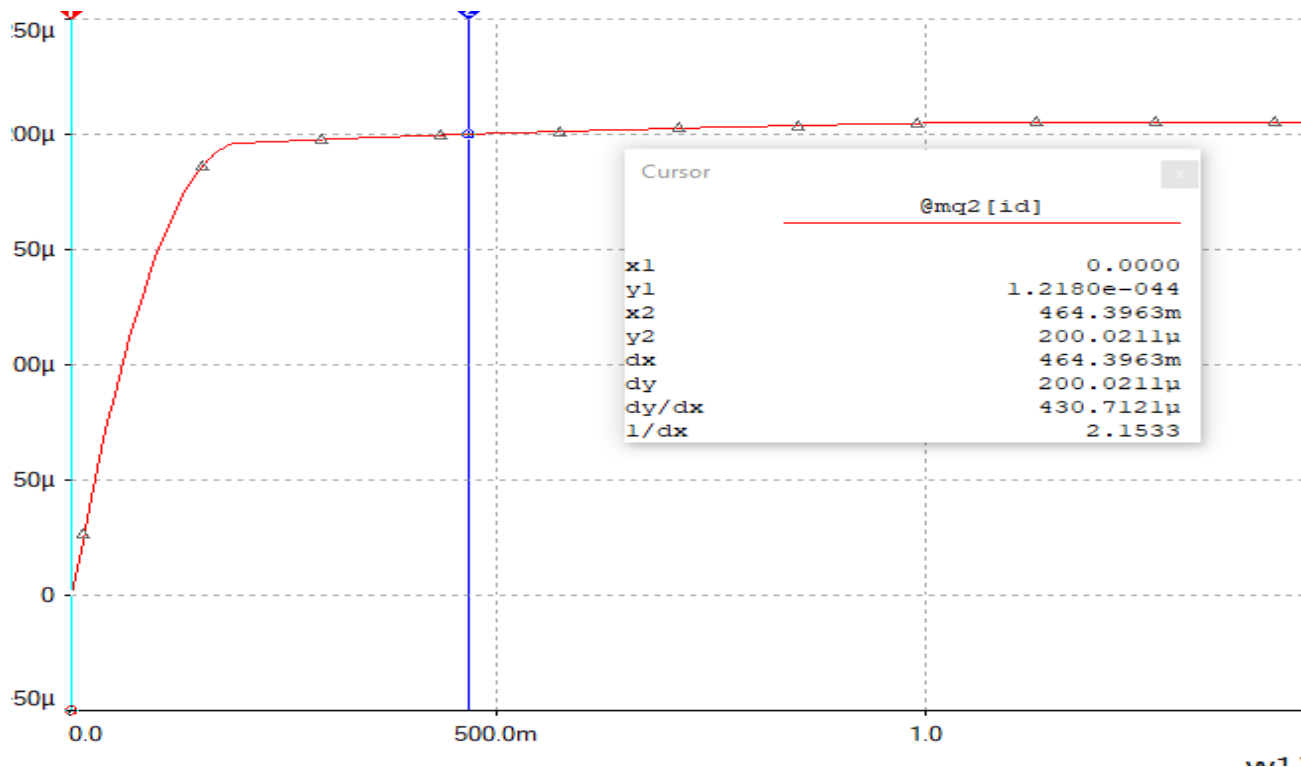
Then $V_{comp} = 2V_{GS} - V_{TH}$

Then $V_{comp} = 2V_{eff} + V_{TH}$

$V_{comp} = 2 \cdot 0.25 + 0.798$

$V_{comp} = 1.3V$

Let plot the relation between I_{out} & V_{out} to obtain the exact value for compliance voltage that will be the value for V_{out} at $I_{out} = 200\mu A$ and this the simulation result:



Figure(24)

We found that : $V_{comp} = 0.64V$

If we need to know the actual current that lout will be when M2 enters the sat we put the vout with 1.3 V and check DC operating point we found that:

DC Operating Point		
1	@mq2[id]	205.29318 u

Figure(25)

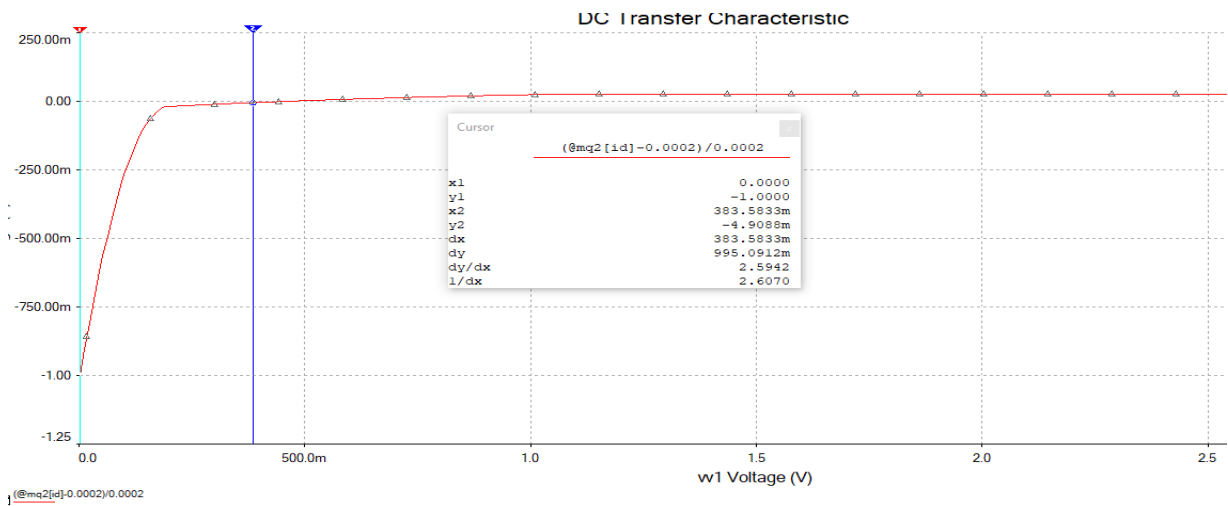
So we found that actual current will be $I_{actual}=205.29318\mu A$

$$Error=((|I_{actual} - I_{ideal}|)/I_{ideal}) \times 100$$

$$Error=((|205.29318-200|)/200) \times 100$$

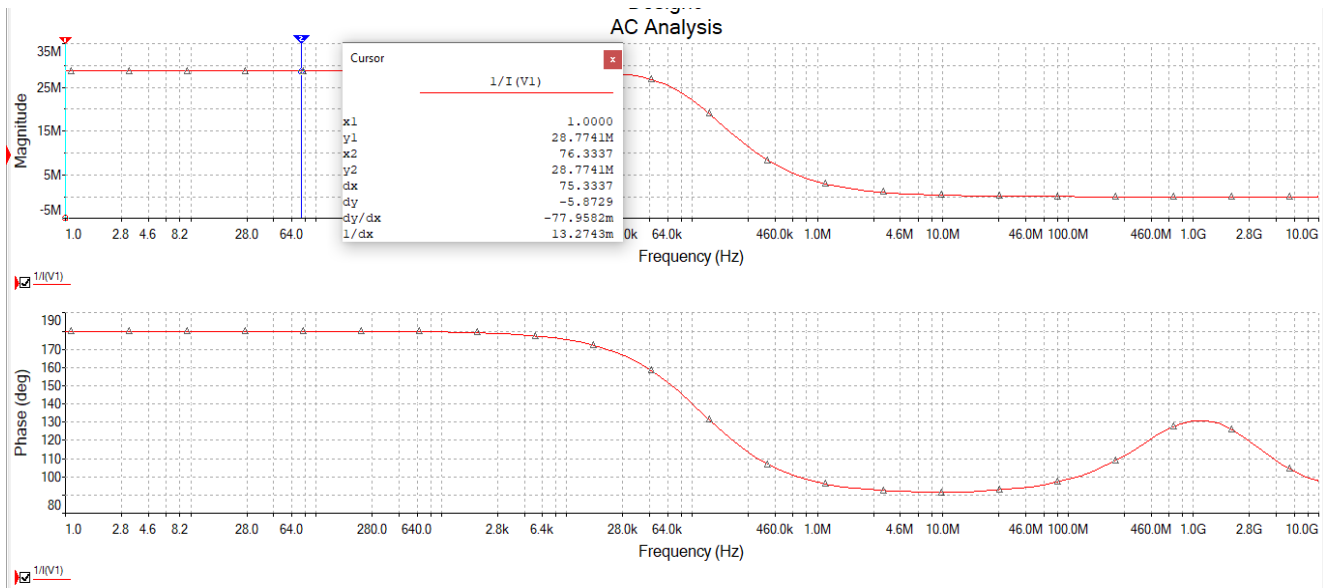
$$Error=2.65\%$$

If we need to plot the percentage error with V_{out} ,this is the simulation result:



Figure(26)

We need to determine R_{out} then we will do AC analysis with AC voltage source that the voltage offset of it is more compliance voltage for example (2V) and this the result simulation:

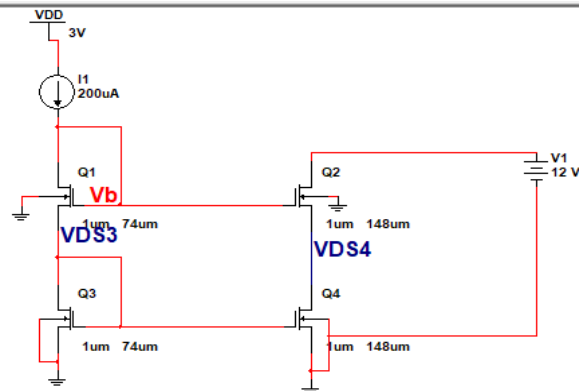


Figure(27)

From simulation result $R_{out}=28.77M\Omega$

2.Second Case:

$I_{in}=200\mu A$ & $I_{out}=400\mu A$ & $v_{eff}=0.25 V$

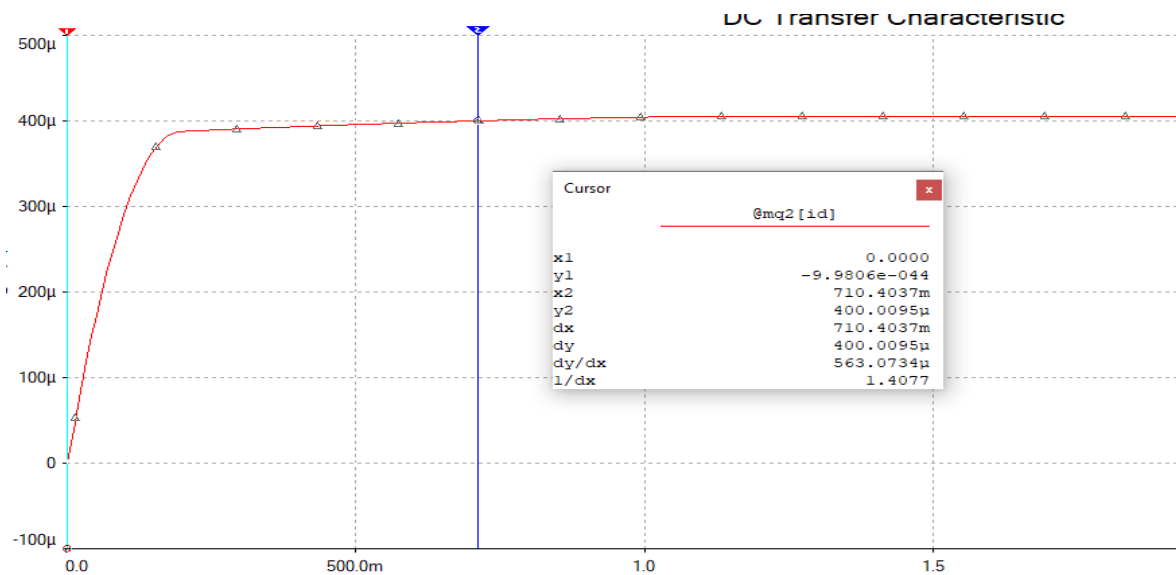


Figure(28)

We will repeat what we did in first case:

For compliance voltage by hand caluclations remains the same: $V_{comp}=1.3V$

Let plot the relation between I_{out} & V_{out} to obtain the exact value for compliance voltage tha will be the value for v_{out} at $I_{out}=400\mu A$ and this the simulation result:



Figure(29)

We found that $V_{comp}=0.71V$

If we need to know the actual current that I_{out} will be when M2 enters the sat we put the V_{out} with 1.3V and check DC operating point we found that:

DC Operating Point		
1	@mq2[id]	405.25000 u

Figure(30)

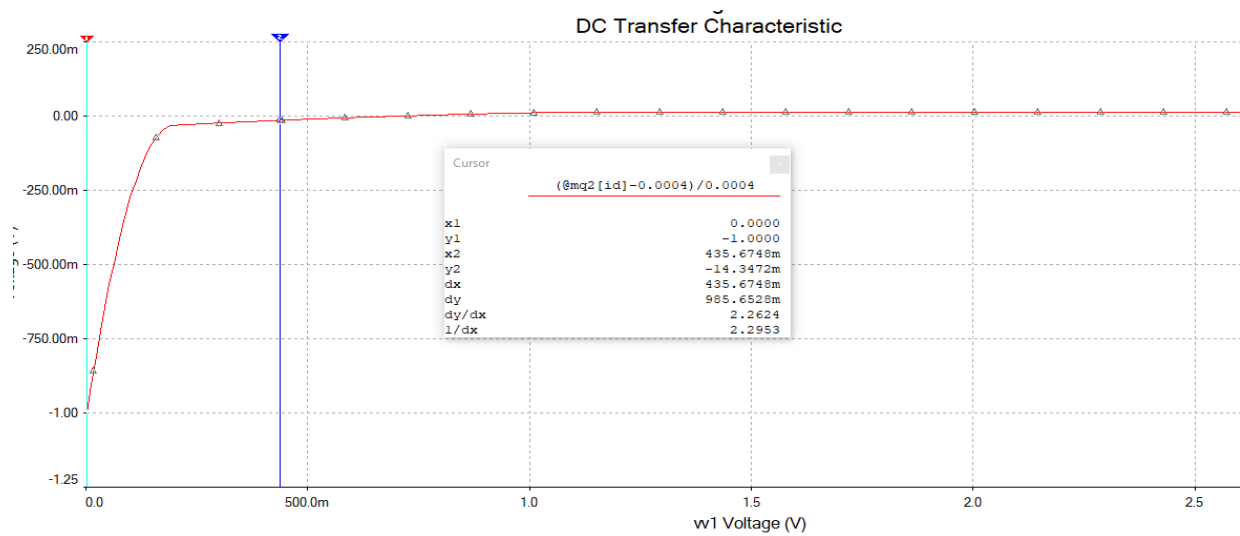
So we found that actual current will be : $I_{actual}=405.25000\mu A$

$$\text{Error} = \left(\frac{|I_{actual} - I_{ideal}|}{I_{ideal}} \right) \times 100$$

$$\text{Error} = \left(\frac{|405.25000 - 400|}{400} \right) \times 100$$

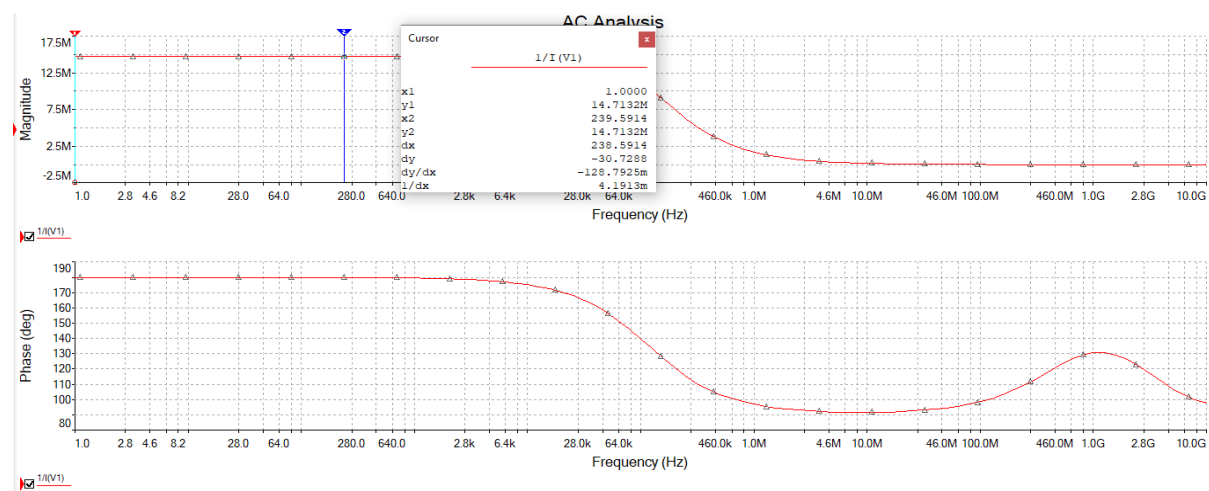
$$\text{Error} = 1.3\%$$

If we need to plot the percentage error with V_{out} , this is the simulation result:



Figure(31)

We need to determine Rout then we will do AC analysis with AC voltage source that the voltage offset of it is more compliance voltage for example (2 V) and this the result simulation:



Figure(32)

From simulation result Rout=14.7MΩ

SUMMARY &CONCLUSTIONS:

1.For simple current mirror:

	Vcomp(hand)	Vcomp(simulation)	Error	Rout
First Case	0.25 V	0.44 V	1.3%	118 K Ω
Second Case	0.25 V	0.67 V	2.56%	60 K Ω

2.For Cascode Current Mirror:

	Vcomp(hand)	Vcomp(simulation)	Error	Rout
First Case	1.3V	0.64 V	2.56%	28.7M Ω
Second Case	1.3V	0.71V	1.3%	14.7 M Ω

Disscution of results:

1.In first case (simple current mirror) if we increase the output current the error increases and the Rout .

2.in second case (cascode current mirror) if we increase the output current the error decrease and the Rout.

Q3.differential pair:

Design hand analysis:

*Input linear range $\geq 0.2\text{v}$

$$v_{od}=v_{eff1}=\sqrt{(I_s/k)} \geq 0.2, I_s=200\mu$$

We will take $v_{eff1}=0.2$

then $k=5*10^{-3}$ knowing that $\mu_{cox}=3.4*10^{-5}$ and $L=1\mu$

Then $w=150\mu$

*ADM ≥ 5

$$ADM = gm * R \text{ and } gm = k * v_{eff1} = 1 * 10^{-3}$$

So $R \geq 5\text{k}$

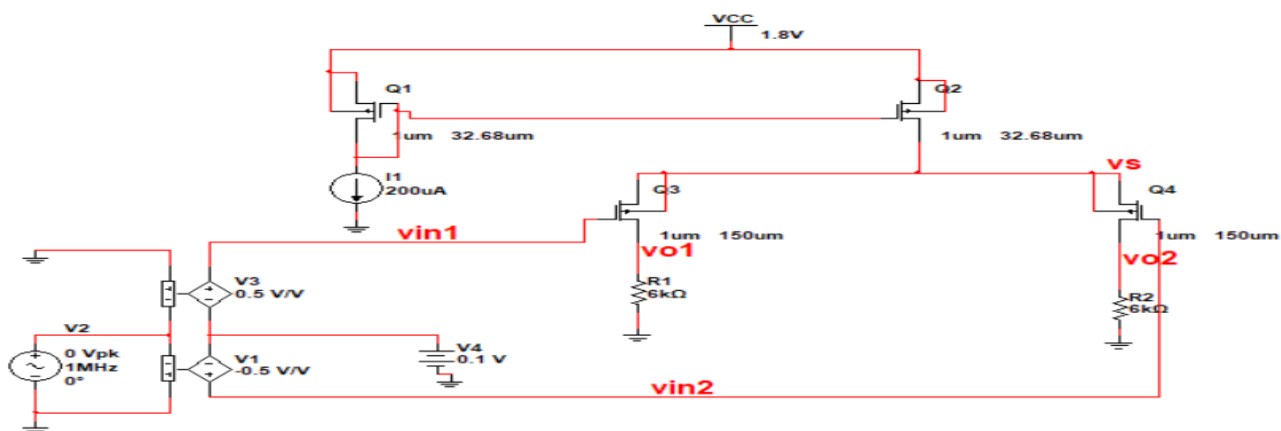
We will tak $R=6\text{k}$

*Differential output swing $\geq 1\text{ vpp}$

$2*(v_{dd}-v_{eff1}-v_{eff2}) \geq 1$ knowing $v_{eff1}=0.2\text{v}$ and $v_{dd}=1.8\text{v}$

$V_{eff2} \leq 1.1\text{v}$ we will take it 0.6v

Then $k_2=1.111*10^{-3}$ if we let $L=1\mu$ then $w=32.68\mu$



Figure(33)

We used a vcvs and gave them same Ac input(differential input) and changed the gain one is 0.5 and the other is -0.5 And the output is raised over DC source(DC common mode).

Input common mode range:

For maximum value we should make sure that the current mirror is on (M2 in sat)

$V_{incm\ max}=v_{dd}-v_{sg1}-v_{eff2}=1.8-(0.2+0.887)-0.6=0.113\text{v}$

For minimum value we should make sure that (M1 in sat)

$V_{incm\ mini}=0.5\cdot I_s\cdot R-l_{vthpl}=-0.287\text{v}$

DC Q-point:

DC Operating Point			
1	@mq3[id]	-94.37275 u	ID for m1
2	@mq1[id]	200.00000 u	ID for m2
3	@mq2[id]	-188.74551 u	ID for m2
4	@mq4[id]	-94.37275 u	ID for m1
5	V(vs)-V(vcc)	-687.69800 m	VDS2
6	V(vcc)-V(vg)-0.887	542.94963 m	Veff2
7	V(vo1)-V(vs)	-546.06548 m	VDS1
8	V(vs)-V(vin1)-0.887	125.30200 m	Veff1

Figure(34)

$ID3=ID4=100\mu$ from table 94.37 μ

$ID2=ID1=200\mu$ from table 188.74 μ

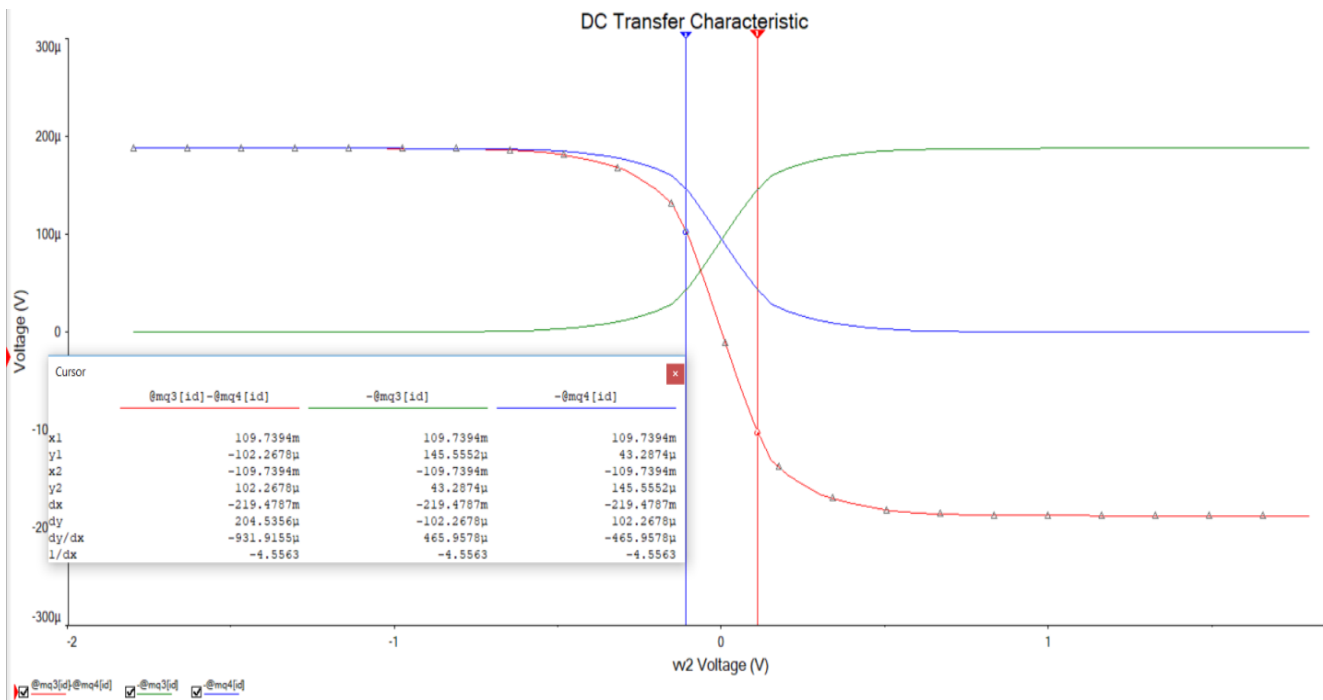
$VDS2=VIN+VSG1-VDD=-0.613$ from table 0.688

V_{eff2} from design 0.6 from table 0.543

$VDS1=0.5I_s\cdot R-(VIN+VSG)=-0.687$ from table -0.546

From design 0.2 from table 0.125 big error due to change in current and error in μ_{cox} calculation and model error too.

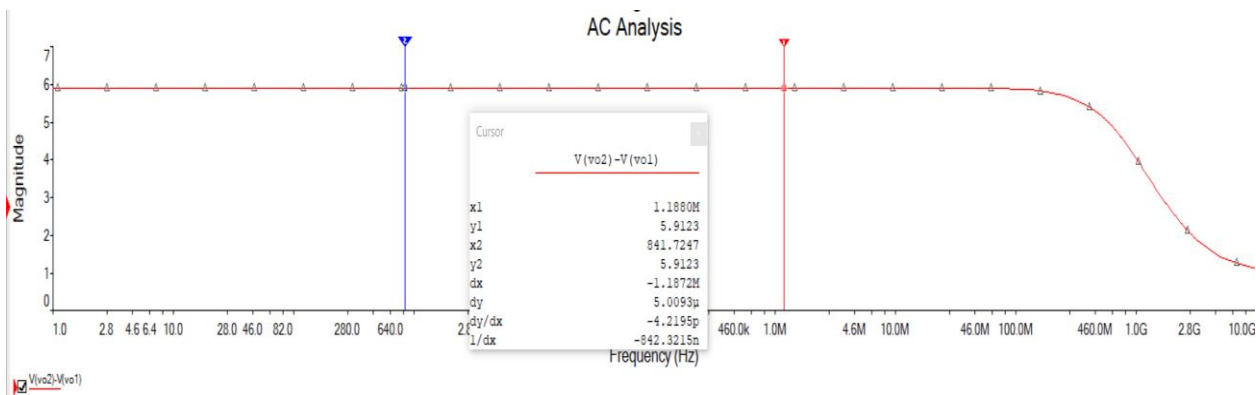
DC sweep for vid:



Figure(35)

We can see that linear input range is higher than 0.2v about 0.22v.

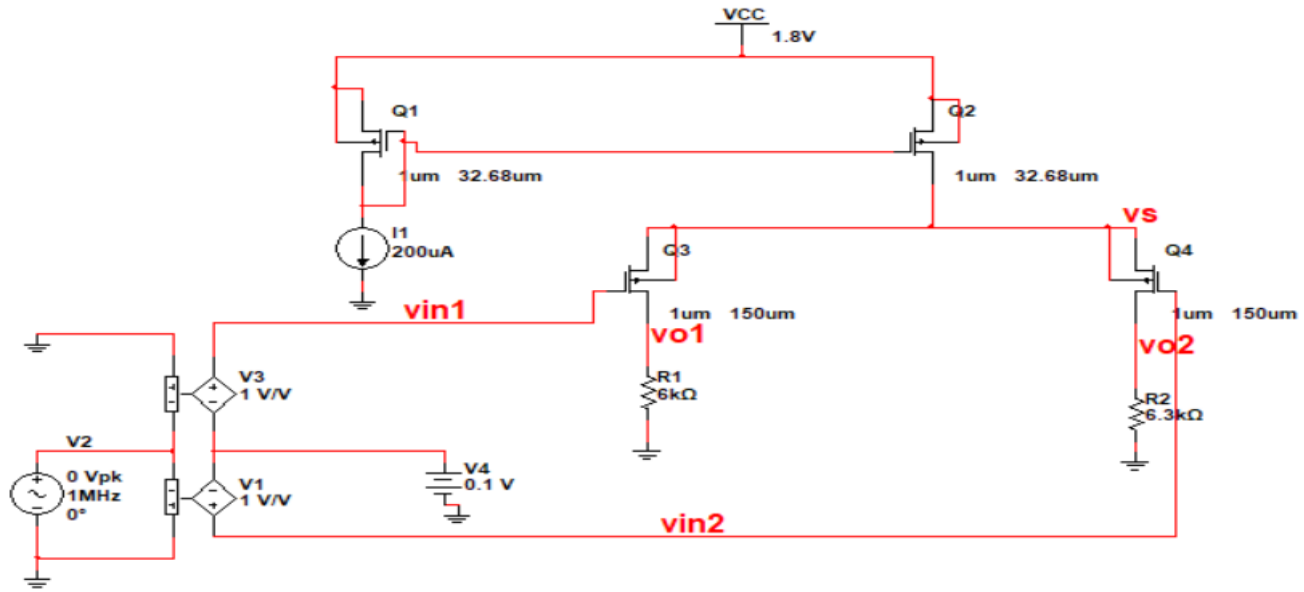
AC analysis for ADM:



Figure(36)

As we see ADM=5.9123 >5

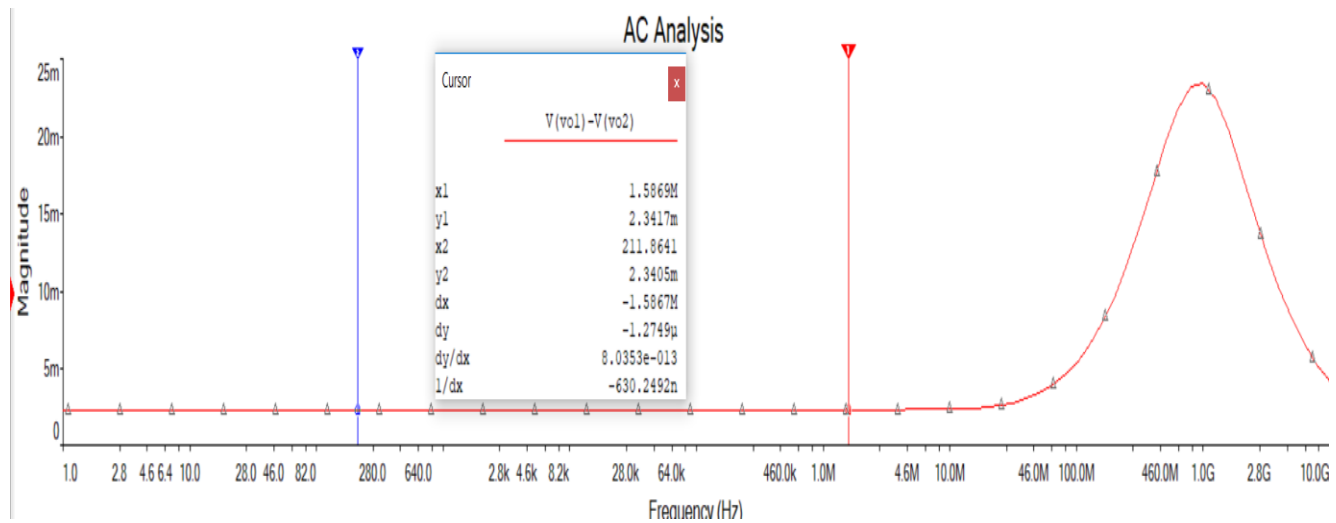
ACM-DM AC analysis:



Figure(37)

We changed the vcvs from (0.5 and -0.5) to (0.5 for both) to be common mode ,and on of the resistors R from 6k to 6.3k(+5%error).

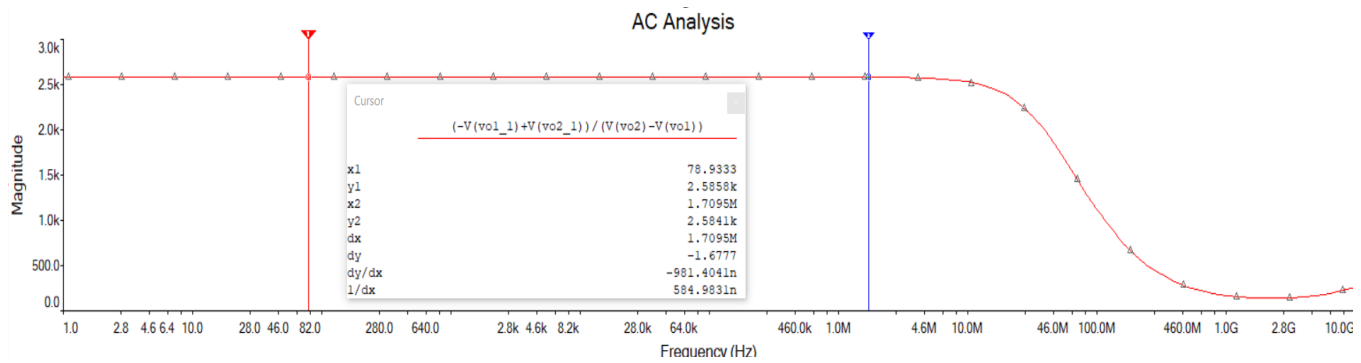
ACM-DM is should be so small= $gm \Delta R / (1 + gm^2 ro_2)$ approximately equal $\Delta R / 2ro_2$.



Figure(38)

We get ACM-DM=0.00234 which is small value as we expected.

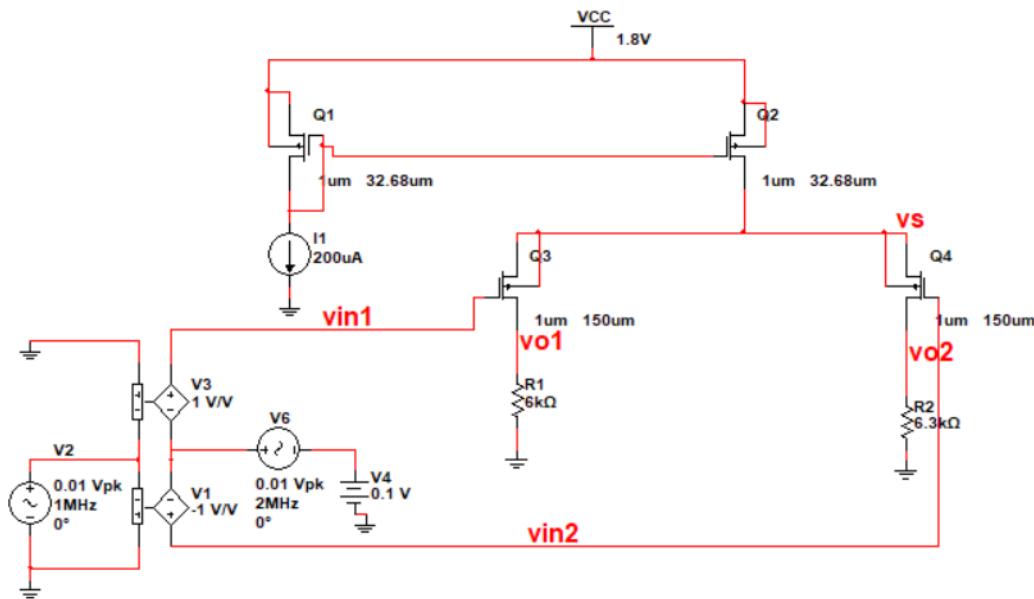
CMRR VS Frequency:



Figure(39)

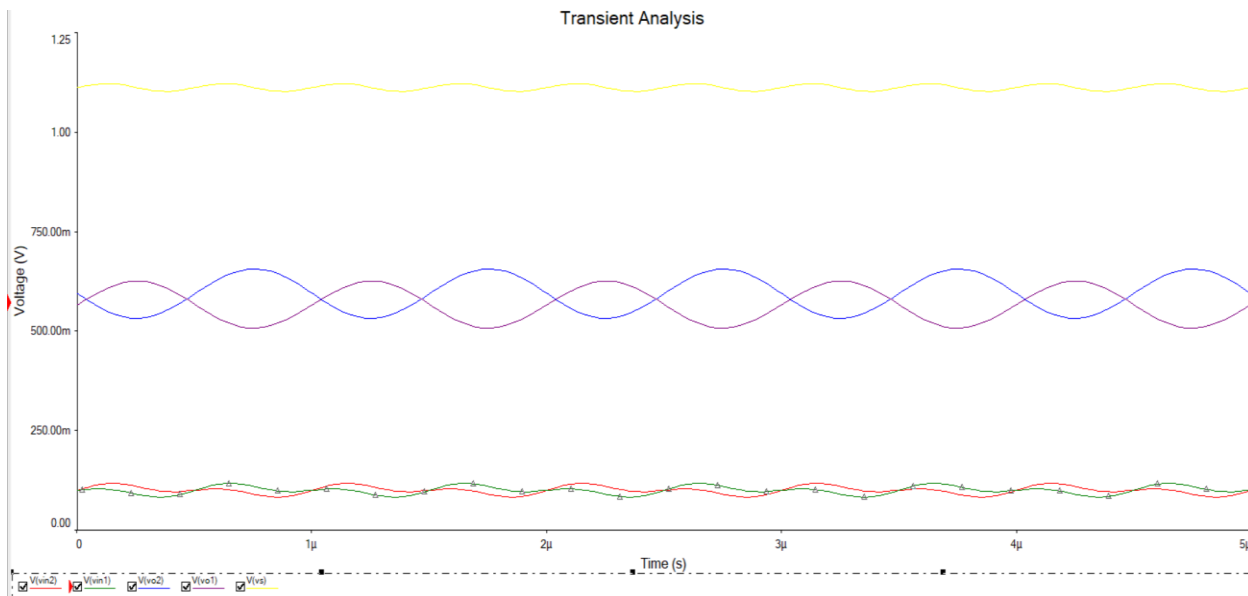
$CMRR = ADM/ACM_DM = 5.9123/0.00234 = 2527$ near to the value we got and it's high ratio and that is good

Transient analysis:



Figure(40)

We changed vcv's to 1 and -1 and connected the input to as 0.01peak and 1MHZ as differential input and used another AC source with 0.01peak and 2MHZ as AC common mode input beside the battery with 0.5v which is in range of input as we solved in a (0.115v and - 0.287v) and keep the 5% error in R.

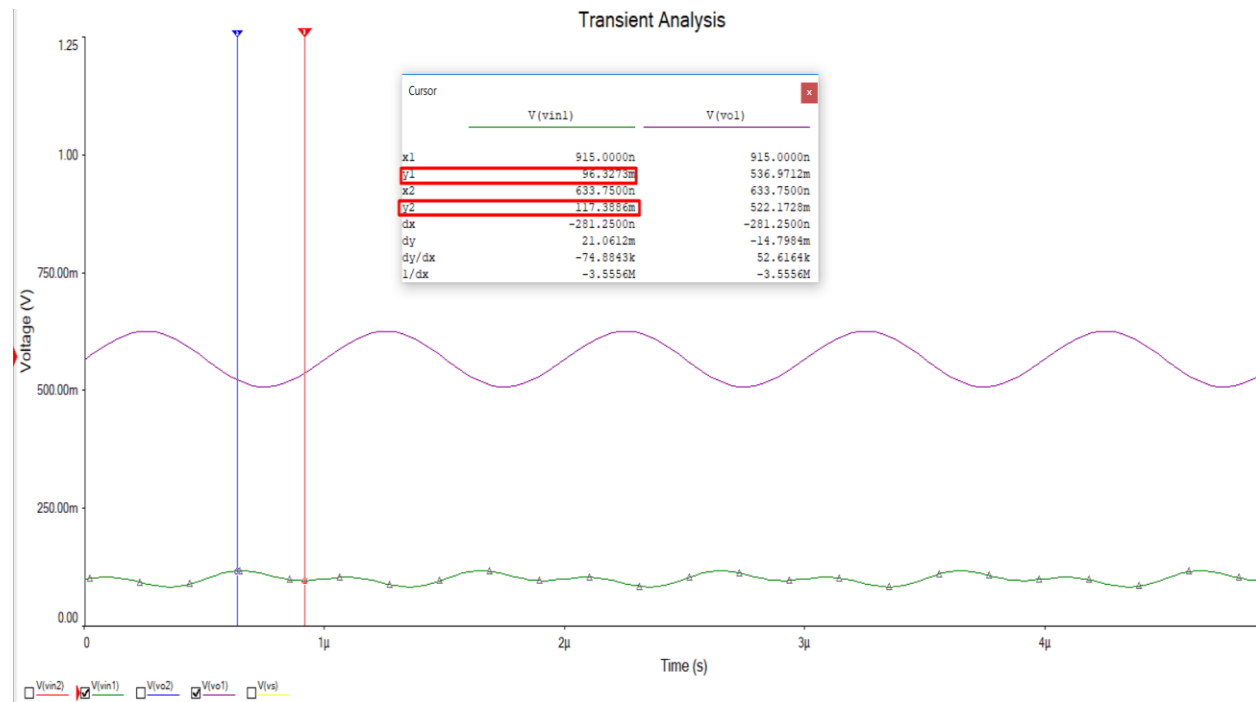


Figure(41)

Comments for transient:

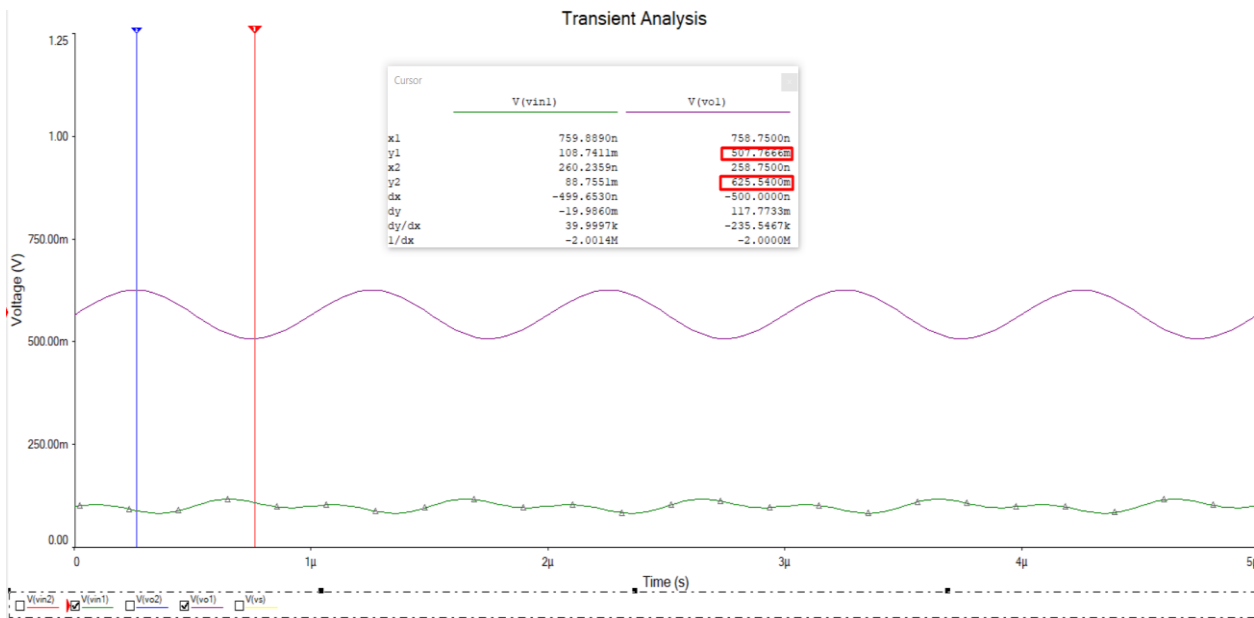
The input is 2 sins with different frequencies and coffients raised on proper dc value =0.1volt , and the output has different frequency from input and have no distortion too .

Gain of vout1/vin1:



Figure(42)

Vin1 amplitude=0.5(maxmum-minimum)=0.5(117.4-96.3)=10.55mv.



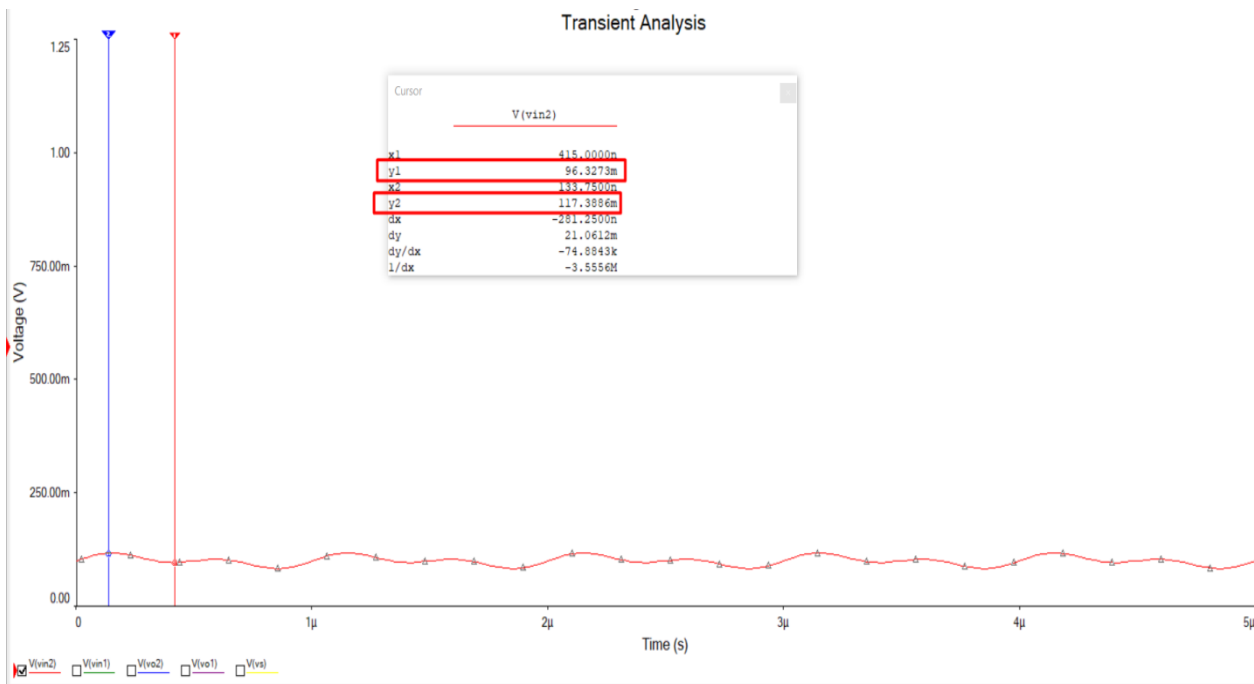
Figure(43)

$V_{out1} \text{ amplitude} = 0.5(625.5 - 507.8) = 58.85 \text{ mV}$

$\text{Gain} = 58.85 / 10.55 = 5.578 > 5$

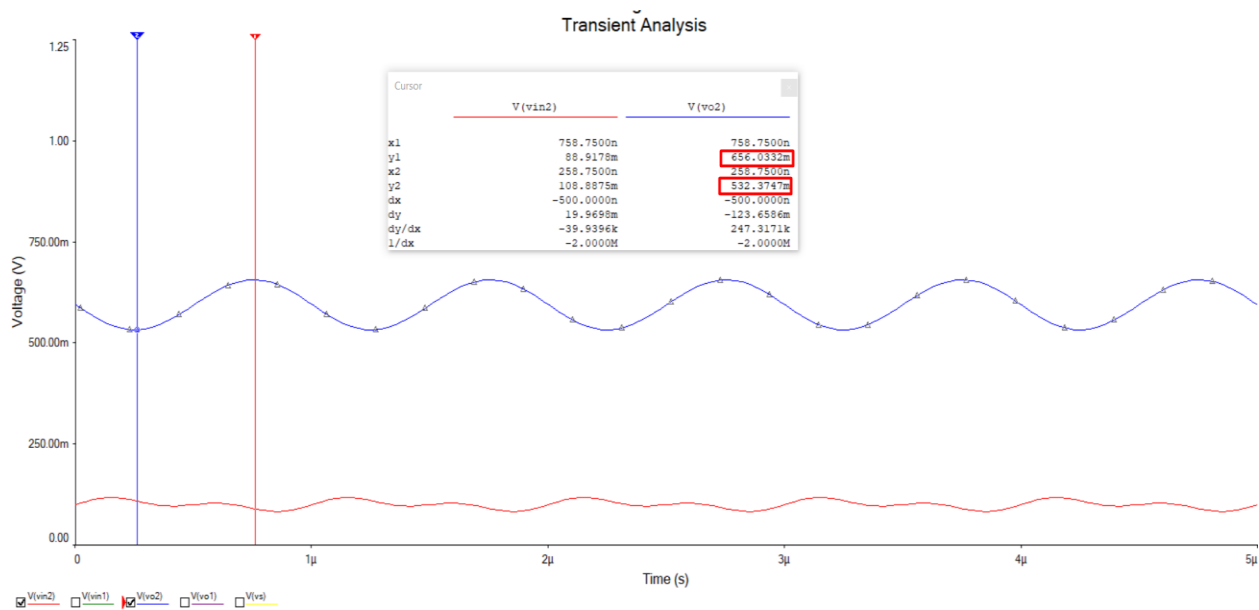
The gain is lower than differential gain due to asymmetric R and Acm-dm.

Gain of v_{out2}/v_{in2} :



Figure(44)

$V_{in} \text{ amplitude} = 0.5(117.4 - 96.3) = 10.35 \text{ mV}$



Figure(45)

$V_{out\ amplitude} = 0.5(656 - 532.4) = 61.8\text{mV}$

Gain = $61.8 / 10.35 = 5.971$ higher than previous gain due to asymmetric in R

Vp :

Vp is high because it has DC value equal nearly $v_{dd} - v_{eff2} = 1.2$ approximately and added to it the AC value

Summary of Result:

Design result:

Transistor	current	veff	W/L
M1	100μ	0.2	150
M2	200μ	0.6	32.7
R=6K			
Input common mode range (0.113 to -0.287)			

Simulation results:

Input linear range	0.22volt
ADM	5.97
ACM-DM	0.0023
CMRR	2530